

NEWS RELEASE

For Immediate Release

CYBEROPTICS SEMICONDUCTOR ANNOUNCES AVAILABILITY OF EX-QS WAFER MAPPING SENSOR

Offers the same high-performance detection capabilities as EX-Q sensor but in a smaller package

BEAVERTON, Ore. -- September 12, 2005 -- CyberOptics Semiconductor, Inc. today announces the availability of its high-performance wafer mapping sensors in a smaller package to accommodate applications where space is limited or a smaller sensor footprint is desired. The EX-QS features the same capabilities as standard size EX-Q mappers, which are highly valued for their extremely reliable detection of semiconductor wafers and slotting errors in cassettes or FOUPs.

Like the standard EX-Q, the EX-43QS and EX-73QS sensors utilize reflective laser technology, and optimize the sensors' optical plane geometry to virtually eliminate any potential for stray reflections from FOUPs, cassettes, or other wafers. As a result, these sensors can quickly and reliably detect all types of wafers regardless of diameter, edge geometry, thickness or coating. They utilize laser transmitters and receivers fine-tuned for maximum sensitivity to excel at detecting dark wafers at factory gain settings and are compatible with flatted or notched wafers of any size including 300mm. The EX-QS employs an extremely thin (0.05 mm) laser stripe combined with multiple apertures and spatial filtering to reduce noise and ensure consistent detection of thin and cross-slotted wafers at one gain setting.

These sensors are insensitive to interference from the mapping environment because their patented dual and wide beam technologies and built-in ambient light filter minimize stray reflections and fluorescent lighting influences. The EX-QS sensors have no moving parts, thus eliminating any potential for particulate contamination; and because they employ reflective technology, the sensors are non-intrusive, thereby mitigating the chance of wafer damage during mapping.

All these features combine to improve overall mapping accuracy and make the EX-QS an ideal high-performance replacement for other reflective sensors that are challenged by highly reflective, dark or ultra-thin wafers manufactured today.

"Our EX-QS is a highly reliable sensor and an ideal solution for areas where space is limited. It is an excellent drop-in replacement for other reflective sensors currently challenged by newer, less reflective wafer coatings," said Craig Ramsey, General Manager for CyberOptics Semiconductor. "Our EX-QS and EX-Q sensors offer semiconductor manufacturers the assurance not only of the most robust components on the market today, but also of a savings in time and money through greatly reduced detection errors."

The EX-QS Series Class 1 sensors are an easy to use “off-the-shelf” solution that requires no amplification or signal conditioning, and can be mounted on wafer handling devices. They come in two stand-off distances: 1.5-inch and 2.2-inch, have operating ranges from 1.4- to 2.35-inches, and conform to IEC 60825-1 (2001-08) laser safety and to the laser safety requirements of SEMI S2-0200.

EX-QS Wafer Mapping Sensor Key Specifications

- Method of detection: Dual Wide Beam
- Stand-off distance: EX-43QS – 1.5-inch; EX-73QS – 2.2-inches
- Maximum detecting distance: EX-43QS – 1.4- to 1.6-inches; EX73QS – 2.05- to 2.35-inches
- Current consumption: 130mA typical
- Response time: 400µs max.
- Minimum pulse width: 5 ms
- Operating temperature: 32 to 104 degrees F (0 to 40 degrees C)

Pricing & Availability

The EX-QS wafer mapping sensors are available now. Attractive volume discounts are available.

Support

CyberOptics Semiconductor’s dedicated team of Technical Support Engineers are available to assist with wafer mapping issues by email at CSsupport@cyberoptics.com or by phone at (800) 366-9131 from 8 AM to 5 PM PDT Monday through Friday.

About CyberOptics Semiconductor

CyberOptics Semiconductor is a subsidiary of CyberOptics Corp. (Nasdaq: CYBE), one of the world’s leading providers of process yield and throughput improvement solutions for electronic assembly and semiconductor capital equipment companies. For more information, visit the web site at: www.CyberopticsSemi.com, e-mail CSsales@cyberoptics.com, or call 800-366-9131.

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